

**Notice of References Cited**

Application/Control No.

10/754,815

Applicant(s)/Patent Under  
Reexamination  
NAKAYA ET AL.

Examiner

Nhan T. Le

Art Unit

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Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

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